

**Notice of References Cited**

Application/Control No.

09/885,744

Applicant(s)/Patent Under  
Reexamination  
NIIMI ET AL.

Examiner

Khiem D Nguyen

Art Unit

2823

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,136,654	10-2000	Kraft et al.	438/287
	B	US-6,391,724	05-2002	Dae-Gyu Park	438/279
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Park et al. Pub. US 2001/027004 Semiconductor Device Having Capacitor And Method Of Manufacturing The Same, Aug. 16, 2001
	V	Weimer et al. Pub. US 2001/0014522 Forming A Conductive Structure In A Semiconductor Device, Aug. 16, 2001.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.